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Exam. Init.	Ref. Des.	Document Number	Date	Name	Cla		Sub Class	Filing Date App.
			Foreign	Patent Docu	ıment	s		
CA	A51	6,002,925	12/14/99	Vu et al.]	3/24/97
CA	A50	6,343,207	1/29/02	Hessel et al.				11/3/98
LA	A49	6,539,066	3/25/03	Heinen	—	一十		11/10/99
Exam. Init.	Ref. Des.	Document Number	Date	Name	Cla	88	Sub Class	Filing Date App.
		<u> </u>	U.S. Pa	atent Docum	nents			
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U.S. Patent Documents See Page 1			Foreign Patent Document		ents	Other Art		
O O	(Use se	everal sheets if nece	2/12/02				2681	
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4		n Disclosure	STATEMENT	BEHRENS	ET AL.			
List of P	atents ar	nd Publications f	s Applicants	Į · · ·				
Lõun	F 10-	(negmed)	SILA:078	1 *			10/075,122	
EARM	DTO-	1449 (modified)	Attv. Docke	Atty. Docket No.			Serial No.	

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Examiner: Chappah Date Considered: 9/23/org

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.